

Search Notes**Application/Control No.**

10/624,456

Examiner

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Applicant(s)/Patent under Reexamination

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Art Unit**SEARCHED**

Class	Subclass	Date	Examiner
455	296 300 301	4/26/2006	LN
	106		
330	170	4/26/2006	LN
UDATE	SEARCH	10/17/2007	LN
	ALL ABOVE		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPG-PUB; USPAT; EPO; JPO; DERWENT) SEE SEARCH HISTORY	4/26/2006	LN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner